Se	arch	Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination
10/052,122	NISHIDA ET AL.
Examiner	Art Unit
Charlotte M. Baker	2626

	SEARCHED		
Class	Subclass	Date	Examiner
358	1.9	2/2/2006	СМВ
358	518	2/2/2006	СМВ
358	523	2/2/2006	СМВ
358	3.23	2/2/2006	СМВ
382	167	2/2/2006	СМВ
355	85	2/2/2006	СМВ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
358	1.9	2/2/2006	СМВ
358	518,523	2/2/2006	СМВ
358	3.23	2/2/2006	СМВ
382/167	', 355/85	2/2/2006	СМВ

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Consulted Primary Examiner Madeline Nguyen	1/26/2006	СМВ
Consulted Primary Examiner Jerome Grant II	2/1/2006	СМВ
Inventor Search	2/2/2006	СМВ